

Title (en)

A SYSTEM AND METHOD FOR THIN FILM QUALITY ASSURANCE

Title (de)

SYSTEM UND VERFAHREN ZUR DÜNNSCHICHT-QUALITÄTSSICHERUNG

Title (fr)

SYSTÈME ET PROCÉDÉ POUR ASSURANCE DE QUALITÉ DE FILMS MINCES

Publication

**EP 2386059 A1 20111116 (EN)**

Application

**EP 09810749 A 20091223**

Priority

- IL 2009001211 W 20091223
- US 14379809 P 20090111

Abstract (en)

[origin: WO2010079474A1] A method of a photovoltaic panel (104) quality control, said method comprising: enabling a relative movement in at least one direction (112) between the photovoltaic panel (104) and a low-resolution scanning imaging unit (132) and capturing successive two-dimensional frames of the scanned area; analyzing the acquired image frames for presence of thin film production defects (144) and communicating to a high resolution image scanning unit (136) locations of said production defects; enabling a relative movement (148) between the photovoltaic panel and the high resolution scanning unit said, movement following the low-resolution unit movement and at least one additional direction parallel to the photovoltaic panel movement direction to acquire and classify the thin film production defects communicated by the low resolution scanning unit; and wherein the low and high resolution scanning units move simultaneously with the same speed (124) across the photovoltaic panel and the speed of the high resolution scanning unit moving in the direction parallel to the thin film movement direction is different from the speed at which the photovoltaic panel moves.

IPC 8 full level

**G01N 21/84** (2006.01)

CPC (source: EP)

**G01N 21/8422** (2013.01); **H02S 50/15** (2014.12); **Y02E 10/50** (2013.01)

Citation (search report)

See references of WO 2010079474A1

Cited by

CN108073844A

Designated contracting state (EPC)

AT BE BG CH CY CZ DE DK EE ES FI FR GB GR HR HU IE IS IT LI LT LU LV MC MK MT NL NO PL PT RO SE SI SK SM TR

DOCDB simple family (publication)

**WO 2010079474 A1 20100715**; EP 2386059 A1 20111116

DOCDB simple family (application)

**IL 2009001211 W 20091223**; EP 09810749 A 20091223